SDAS113B - APRIL 1982 - REVISED DECEMBER 1994

 Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

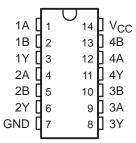
These devices contain four independent 2-input positive-OR <u>gates</u>. They perform the Boolean functions $Y = \overline{A} \cdot \overline{B}$ or Y = A + B in positive logic.

The SN54ALS32 and SN54AS32 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS32 and SN74AS32 are characterized for operation from 0°C to 70°C.

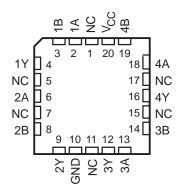
FUNCTION TABLE (each gate)

INP	UTS	OUTPUT
Α	В	Υ
Н	Χ	Н
X	Н	Н
L	L	L

SN54ALS32, SN54AS32 . . . J PACKAGE SN74ALS32, SN74AS32 . . . D OR N PACKAGE (TOP VIEW)



SN54ALS32, SN54AS32 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

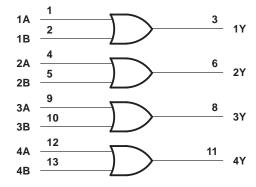
logic symbol†

4.6	1	>1	، ا	
1A 1B	2	≥1	3	1Y
24	4		_	
2A 2B 3A	5		6	2Y
20	9			
	10		8	3Y
3B	12		44	
4A	13		11	4Y
4B				

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

logic diagram (positive logic)



SN54ALS32, SN54AS32, SN74ALS32, SN74AS32 QUADRUPLE 2-INPUT POSITIVE-OR GATES

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A : SN54ALS32	55°C to 125°C
SN74ALS32	0°C to 70°C
Storage temperature range	. −65°C to 150°C

recommended operating conditions

		SN54ALS32			SI	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
loh	High-level output current			-0.4			-0.4	mA
loL	Low-level output current			4			8	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST COMPLIANC		SI	SN54ALS32			SN74ALS32			
PARAMETER	1551 C	TEST CONDITIONS		TYP‡	MAX	MIN	TYP‡	MAX	UNIT	
VIK	$V_{CC} = 4.5 \text{ V},$	I _I = -18 mA			-1.5			-1.5	V	
Voн	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		V	
Vol	V _{CC} = 4.5 V	$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V	
VoL		I _{OL} = 8 mA					0.35	0.5	V	
lį	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA	
lіН	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20			20	μΑ	
I _{IL}	$V_{CC} = 5.5 \text{ V},$	V _I = 0.4 V			-0.1			-0.1	mA	
ΙΟ [§]	$V_{CC} = 5.5 V,$	V _O = 2.25 V	-20		-112	-30		-112	mA	
ICCH	$V_{CC} = 5.5 \text{ V},$	V _I = 4.5 V		1.9	4		1.9	4	mA	
ICCL	$V_{CC} = 5.5 V,$	V _I = 0		2.6	4.9		2.6	4.9	mA	

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L R _L T _A	$\begin{array}{c c} V_{CC} = 4.5 \text{ V to } 5.5 \text{ V,} \\ C_L = 50 \text{ pF,} \\ R_L = 500 \Omega, \\ T_A = \text{MIN to MAX} \\ \hline \\ \text{SN54ALS32} & \text{SN74ALS32} \\ \hline \\ \text{MIN MAX} & \text{MIN MAX} \\ \end{array}$			UNIT
t _{PLH}	A or D	V	3	18	3	14	
^t PHL	A or B	Y	3	16	3	12	ns

 $[\]P$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A : SN54AS32	-55°C to 125°C
SN74AS32	0°C to 70°C
Storage temperature range	-65°C to 150°C

recommended operating conditions

		SN54AS32		S	UNIT			
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.8			0.8	V
IOH	High-level output current			-2			-2	mA
lOL	Low-level output current			20			20	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54AS32			S	UNIT		
PARAMETER	TEST CO	UNDITIONS	MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	UNII
VIK	V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V
Voн	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		V
V _{OL}	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$		0.35	0.5		0.35	0.5	V
lį	$V_{CC} = 5.5 V,$	V _I = 7 V			0.1			0.1	mA
lН	$V_{CC} = 5.5 V,$	V _I = 2.7 V			20			20	μΑ
Ι _Ι L	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.5			-0.5	mA
IO§	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA
Іссн	$V_{CC} = 5.5 \text{ V},$	V _I = 4.5 V		7.3	12		7.3	12	mA
ICCL	$V_{CC} = 5.5 \text{ V},$	V _I = 0		16.5	26.6		16.5	26.6	mA

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L R _L T _A	$\begin{array}{c c} V_{CC} = 4.5 \text{ V to } 5.5 \text{ V,} \\ C_L = 50 \text{ pF,} \\ R_L = 500 \ \Omega, \\ T_A = \text{MIN to MAX} \\ \hline \\ \text{SN54AS32} & \text{SN74AS32} \\ \hline \\ \text{MIN MAX} & \text{MIN MAX} \\ \end{array}$		UNIT	
tPLH	A or P	A or B Y	1	7.5	1	5.8	no
^t PHL	AUID		1	6.5	1	5.8	ns

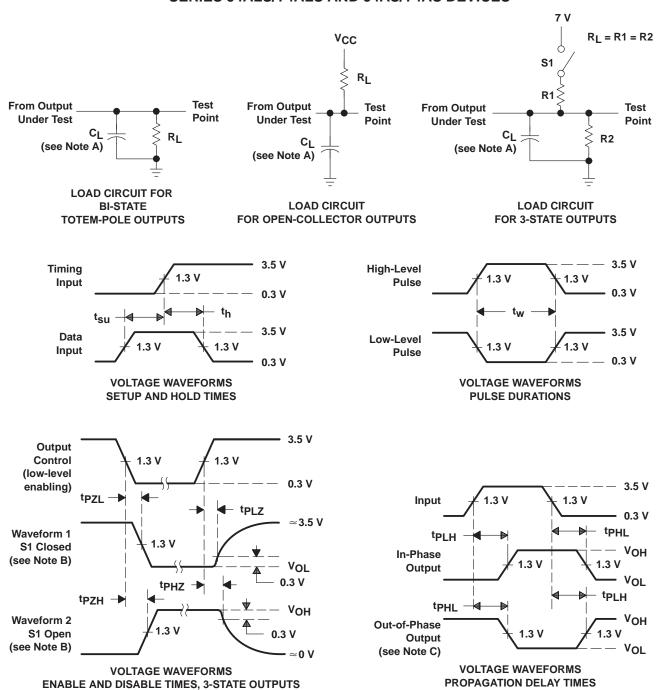
[¶] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: $PRR \le 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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